

## Contents

### Preface *ix*

<b>1</b>	<b>Spectroscopic Ellipsometry: Basic Principles</b>	<b>1</b>
1.1	Spectroscopic Ellipsometry	1
1.1.1	p- and s-Polarized Lights and Fresnel Coefficients	2
1.1.2	Representation of Polarized Lights	3
1.2	Principles of Ellipsometric Measurements	5
1.2.1	Rotating-Analyzer Ellipsometer	6
1.3	Experimental Setup	7
1.3.1	VASE Spectroscopic Ellipsometer	8
1.3.2	IR-VASE Spectroscopic Ellipsometer	9
1.4	Spectroscopic Ellipsometry: General Profiles	10
1.5	Ellipsometric Data for Multilayered System	11
1.6	Dielectric Models	12
1.6.1	Drude Model	13
1.6.2	Lorentz Model	14
1.6.3	Drude-Lorentz Model	16
1.6.4	Sellmeier and Cauchy Models	17
1.7	Chapter Summary	18
	References	18
<b>2</b>	<b>Strongly Correlated Systems: Cuprates and Manganites</b>	<b>19</b>
2.1	Introduction	19
2.2	High-Transition-Temperature Superconducting Cuprates	19
2.2.1	The Crystalline Structure of Cuprates	20
2.2.1.1	The Structure of $\text{La}_{1-x}\text{Sr}_x\text{CuO}_4$	20
2.2.1.2	The Structure of $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$	20
2.2.1.3	The Structure of $\text{Nd}_{2-x}\text{Ce}_x\text{CuO}_4$	21
2.2.2	The Electronic Structure of Cuprates	22
2.3	Colossal Magnetoresistance Manganites	26
2.3.1	Crystal Structure of $\text{La}_{1-x}\text{Sr}_x\text{MnO}_3$	26
2.3.2	The Electronic Structure and Magnetism of LSMO	26

2.3.3	Strong and Weak Correlations in Ambipolar Cuprate Thin-Film Systems	28
2.3.4	Samples	29
2.3.5	Spectroscopic Ellipsometry	31
2.4	Charge Localization in Cuprate Thin Film on Oxide Substrate	37
2.5	Plasmon and High-Energy Exciton Excitations in Cuprate Thin Films	40
2.5.1	Observation of the Low- and High-Energy Plasmons in LSCO/STO Film	40
2.5.2	Observation of the High-Energy Excitons in the LSCO/STO Film	43
2.6	Jahn–Teller Splitting Energy Controls the Phase Transition in Manganite Thin-Film Systems	45
	References	49
<b>3</b>	<b>Two-Dimensional Transition Metal Dichalcogenides</b>	<b>59</b>
3.1	Introduction	59
3.2	Crystal Structures of 2D-TMDs	59
3.2.1	1H-Phase	60
3.2.2	1T and 1T'-Phase	61
3.2.3	1H–1T'-Phase Energetics	61
3.2.4	Arising Electronic Structures	61
3.2.4.1	Indirect-to-Direct Bandgap Transition	61
3.2.4.2	Spin–Orbit Splitting	62
3.2.4.3	1T'-Phase Electronic Band Structure	63
3.2.5	2D-TMD: Excitons	64
3.2.5.1	Excitons in 2D-TMDs	65
3.2.5.2	Excitons and Trions	67
3.2.6	Investigative Objectives for 2D-TMDs	67
3.3	Ellipsometry in Probing Structural Phase Transition and Electronic Structures Monolayer-MoS <sub>2</sub>	68
3.3.1	Experimental Results	70
3.3.1.1	Sample Preparation	70
3.3.1.2	Optical Features of Monolayer-MoS <sub>2</sub>	70
3.3.1.3	Inverted and Fundamental Gaps of 1T'-Phase 2D-TMDs	71
3.3.2	Dynamics of 1H–1T'-Phase Transition	72
3.3.2.1	First-Principle Study: Role of Substrates	72
3.3.3	Analyzing the 1H–1T'-Phase Transition of MoS <sub>2</sub> /Cu	75
3.3.3.1	Optical Characterization of MoS <sub>2</sub> /Cu	75
3.3.3.2	Raman and PL Characterization	76
3.3.3.3	Photoemission Spectroscopic Characterization	77
3.3.4	1H–1T'-Phase Transition of WSe <sub>2</sub> /Au	79
3.3.4.1	Optical Characterization of WSe <sub>2</sub> /Au	80
3.3.4.2	Photoluminescence and Photoemission Characterization of WSe <sub>2</sub> /Au	81
3.3.4.3	Phase Transition Yield of 2D-TMDs	84

3.3.5	Section Conclusion	85
3.4	Three-Dimensional Resonant Exciton in Monolayer-WSe <sub>2</sub>	87
3.4.1	Materials, Methods, and Results	88
3.4.1.1	Sample Growth	88
3.4.1.2	Optical Characterization of Monolayer-WSe <sub>2</sub>	89
3.4.1.3	Exciton Peaks: Temperature Dependence	92
3.4.1.4	Fitting Parameters of $\epsilon_2$ Spectra	94
3.4.2	Effects of Temperature on SOC in 2D TMDs	95
3.4.3	High-Energy Photoluminescence Characterization	97
3.4.4	Power-Dependent Photoluminescence Spectroscopic Study	99
3.4.5	Computational Studies	99
3.4.5.1	High-Energy Resonant Exciton Demonstrated via GW–BSE Calculations	99
3.4.5.2	Comparison Between Wannier–Mott and Resonant Excitons	100
3.4.5.3	Origin of Resonant Exciton: Band Structure Calculations Analysis	101
3.4.6	3D-Features of Resonant Exciton in Monolayer-WSe <sub>2</sub> and Thickness Dependence	103
3.4.7	Estimating Exciton Binding Energy	105
3.4.8	Section Summary	105
3.5	Anisotropic Plasmon Excitations in Quasi-Metallic 2D-TMDs	106
3.5.1	Anisotropic Plasmons in 1T'-Phase 2D-TMDs	107
3.5.1.1	Sample Preparation	107
3.5.1.2	Detection of Plasmon in 1T'-Phase WSe <sub>2</sub> /Au	108
3.5.2	One-Dimensional Plasmon in 1T'-Phase WSe <sub>2</sub>	110
3.5.3	Detecting Plasmons in 1T'-Phase MoS <sub>2</sub> /Au Monolayer	112
3.5.4	Analyzing One-Dimensional Plasmon in 1T'-Phase 2D-TMDs	115
3.5.5	1H–1T'-Phase Transition	116
3.5.6	Section Conclusion	117
	References	118
<b>4</b>	<b>Single-Layer Graphene Systems</b>	<b>131</b>
4.1	Introduction	131
4.2	Crystal and Electronic Structure of Graphene	131
4.2.1	Electronic Band Structure of Graphene	132
4.3	Optoelectronic Properties of Graphene	134
4.4	Spectroscopic Ellipsometry Study of Graphene	135
4.4.1	Measurement and Data Analysis of Graphene	135
4.5	Resonant Excitons in Graphene	137
4.6	Substrate-Induced Manipulation of Many-Body Effects	138
4.7	Conclusion and Outlook	141
	References	142
<b>5</b>	<b>Nickelate Systems</b>	<b>149</b>
5.1	Introduction	149
5.2	Crystal Structure	149

5.3	Electronic Structures and Ni3d-Orbital Physics	150
5.4	Phase Diagram and Metal–Insulator Transitions of RNiO <sub>3</sub> Systems	151
5.4.1	Magnetic Phases in RNiO <sub>3</sub> Systems	152
5.5	Optical Characterization via Spectroscopic Ellipsometry	153
5.5.1	Effects of Epitaxial Effects on the Electronic Correlations of Nickelate Thin Films	154
5.5.2	Long-Range Spin Ordering in Nickelate Thin Films	155
5.6	Conclusion and Outlook	159
	References	161
<b>6</b>	<b>Future Development and Applications of Spectroscopic Ellipsometry</b>	<b>167</b>
6.1	Development of Mueller Matrix Imaging Techniques in Spectroscopic Ellipsometry	167
6.2	<i>In Situ</i> Analysis of Langmuir Monolayers	169
6.3	Emergent Properties at Two-Dimensional Interfaces	170
6.4	Micro Devices and Integrated Circuits	171
6.5	Metamaterial Research	172
6.6	Organic Electronics	172
6.7	Biological Materials and Medicines	173
6.8	Anisotropic Materials	173
6.9	Process Control Analysis	173
	References	174
	<b>Index</b>	<b>181</b>